ICX408AK

Diagonal 6mm (Type 1/3) CCD Image Sensor for NTSC Color Video Cameras

Description

The ICX408AK is an interline CCD solid-state image sensor suitable for NTSC color video cameras with a diagonal 6mm (Type 1/3) system. Compared with the conventional product ICX058CK, basic characteristics such as sensitivity, smear, dynamic range and S/N are improved drastically.

This chip features a field period readout system and an electronic shutter with variable charge-storage time.

This chip is suitable for applications such as surveillance cameras, automotive cameras, etc.

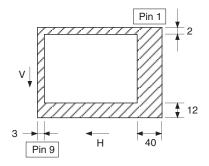
16 pin DIP (Plastic)

Features

- High sensitivity (+6dB compared with the ICX058CK)
- Low smear (-15dB compared with the ICX058CK)
- High D range (+4dB compared with the ICX058CK)
- High S/N
- High resolution and low dark current
- · Excellent antiblooming characteristics
- Ye, Cy, Mg, and G complementary color mosaic filters on chip
- Continuous variable-speed shutter
- No voltage adjustment

(Reset gate and substrate bias need no adjustment.)

Reset gate: 5V driveHorizontal register: 5V drive



Optical black position (Top View)

Device Structure

• Interline CCD image sensor

• Image size: Diagonal 6mm (Type 1/3)

Number of effective pixels: 768 (H) × 494 (V) approx. 380K pixels
 Total number of pixels: 811 (H) × 508 (V) approx. 410K pixels

• Chip size: 5.59mm (H) \times 4.68mm (V) • Unit cell size: 6.35 μ m (H) \times 7.40 μ m (V)

Optical black: Horizontal (H) direction: Front 3 pixels, rear 40 pixels

Vertical (V) direction : Front 12 pixels, rear 2 pixels

Number of dummy bits: Horizontal 22

Vertical 1 (even fields only)

Substrate material: Silicon

Super HAD CCD TM

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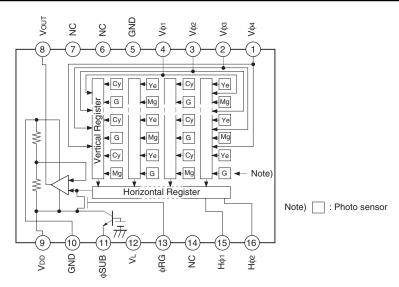
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Block Diagram and Pin Configuration (Top View)



Pin Description

Pin No.	Symbol	Description	Pin No.	Symbol	Description
1	V ф4	Vertical register transfer clock	9	VDD	Supply voltage
2	Vфз	Vertical register transfer clock	10	GND	GND
3	V ф2	Vertical register transfer clock	11	φSUB	Substrate clock
4	Vф1	Vertical register transfer clock	12	VL	Protective transistor bias
5	GND	GND	13	φRG	Reset gate clock
6	NC		14	NC	
7	NC		15	Нф1	Horizontal register transfer clock
8	Vouт	Signal output	16	Нф2	Horizontal register transfer clock

Absolute Maximum Ratings

	Item						
	Vdd, Vout, фRG – фSUB	-40 to +8	V				
Against &CLIP	Vφ1, Vφ3 – φSUB	-50 to +15	V				
Against φSUB	Vφ2, Vφ4, VL – φSUB	-50 to +0.3	V				
	Hφ1, Hφ2, GND – φSUB	-40 to +0.3	V				
	Vdd, Vout, фRG – GND	-0.3 to +20	V				
Against GND	Vφ1, Vφ2, Vφ3, Vφ4 – GND	-10 to +18	V				
	Hφ1, Hφ2 – GND	-10 to +6	V				
Against W	Vφ1, Vφ3 – VL	-0.3 to +28	V				
Against V∟	Vφ2, Vφ4, Hφ1, Hφ2, GND – VL	-0.3 to +15	V				
	Voltage difference between vertical clock input pins	to +15	V	*1			
Between input clock pins	Ηφ1 – Ηφ2	-6 to +6	V				
pino	Hφ1, Hφ2 – Vφ4	-14 to +14	V				
Storage temperature	Storage temperature						
Operating temperature	Operating temperature						

^{*1 +24}V (Max.) when clock width < 10μ s, clock duty factor < 0.1%.

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Bias Conditions

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Supply voltage	VDD	14.55	15.0	15.45	V	
Protective transistor bias	VL	*1				
Substrate clock	φSUB	*2				

^{*1} VL setting is the VvL voltage of the vertical transfer clock waveform, or the same power supply as the VL power supply for the V driver should be used.

DC Characteristics

Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Supply current	IDD		4	6	mA	

Clock Voltage Conditions

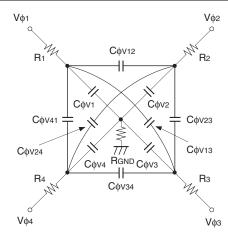
Item	Symbol	Min.	Тур.	Max.	Unit	Waveform diagram	Remarks
Readout clock voltage	VvT	14.55	15.0	15.45	V	1	
	VvH1, VvH2	-0.05	0	0.05	V	2	VvH = (VvH1 + VvH2)/2
	VvH3, VvH4	-0.2	0	0.05	V	2	
	VVL1, VVL2, VVL3, VVL4	-8.0	-7.0	-6.5	٧	2	VvL = (VvL3 + VvL4)/2
	Vφv	6.3	7.0	8.05	V	2	$V \phi v = V v + n - V v + n (n = 1 \text{ to } 4)$
Vertical transfer clock	Vvнз — Vvн	-0.25		0.1	V	2	
voltage	VvH4 — VvH	-0.25		0.1	V	2	
	Vvhh			0.3	V	2	High-level coupling
	Vvhl			0.3	V	2	High-level coupling
	Vvlh			0.3	V	2	Low-level coupling
	VVLL			0.3	V	2	Low-level coupling
Horizontal transfer	Vфн	4.75	5.0	5.25	V	3	
clock voltage	VHL	-0.05	0	0.05	V	3	
	VфRG	4.5	5.0	5.5	٧	4	Input through 0.1µF capacitance
Reset gate clock	Vrglh – Vrgll			0.4	V	4	Low-level coupling
voltage	VRGL - VRGLm			0.5	V	4	Low-level coupling
	VRGH	V _{DD} +0.3	V _{DD} +0.6	V _{DD} +0.9	V	4	
Substrate clock voltage	Vфsuв	21.0	22.0	23.5	V	5	

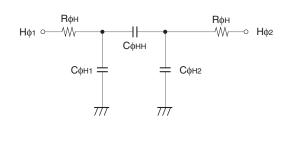
^{*2} Do not apply a DC bias to the substrate clock pin, because a DC bias is generated within the CCD.



Clock Equivalent Circuit Constant

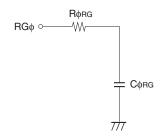
Item	Symbol	Min.	Тур.	Max.	Unit	Remarks
Capacitance between vertical transfer	Сфу1, Сфу3		1500		pF	
clock and GND	Сфу2, Сфу4		1000		pF	
	СфV12, СфV34		820		pF	
Capacitance between vertical transfer	Сф∨23, Сф∨41		330		pF	
clocks	СфV13		120		pF	
	СфV24		100		pF	
Capacitance between horizontal transfer clock and GND	Сфн1, Сфн2		75		pF	
Capacitance between horizontal transfer clocks	Сфнн		22		pF	
Capacitance between reset gate clock and GND	Сфяс		5		pF	
Capacitance between substrate clock and GND	Сфѕив		270		pF	
Vertical transfer alogic porior register	R ₁ , R ₃		100		Ω	
Vertical transfer clock series resistor	R2, R4		150		Ω	
Vertical transfer clock ground resistor	RGND		68		Ω	
Horizontal transfer clock series resistor	Rфн		15		Ω	
Reset gate clock series resistor	Rørg		50		Ω	





Vertical transfer clock equivalent circuit

Horizontal transfer clock equivalent circuit

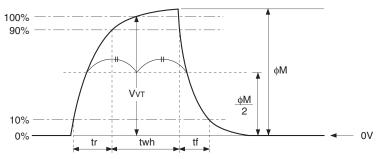


Reset gate clock equivalent circuit

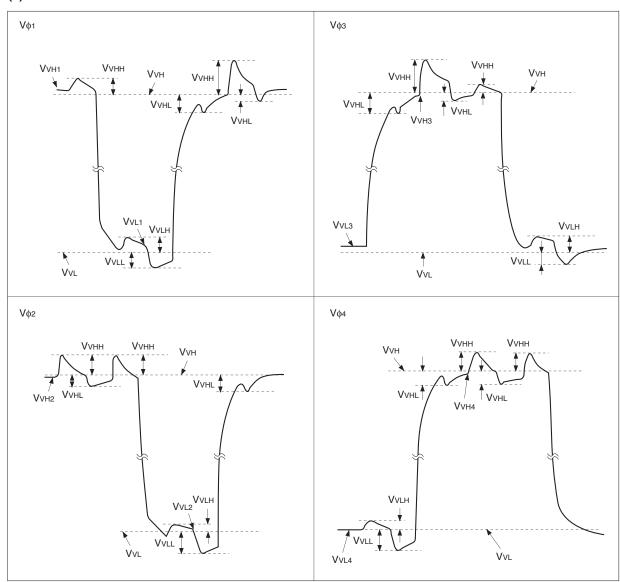


Drive Clock Waveform Conditions

(1) Readout clock waveform



(2) Vertical transfer clock waveform



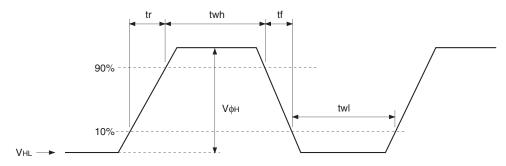
$$VvH = (VvH1 + VvH2)/2$$

$$V_{VL} = (V_{VL3} + V_{VL4})/2$$

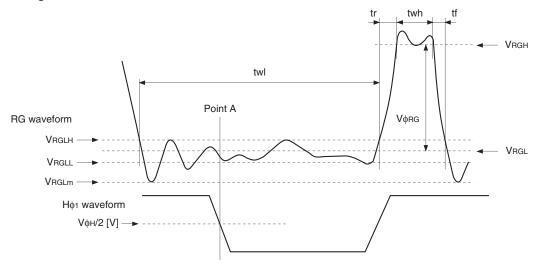
$$V\phi V = VVHN - VVLN (n = 1 \text{ to } 4)$$



(3) Horizontal transfer clock waveform



(4) Reset gate clock waveform



VRGLH is the maximum value and VRGLL is the minimum value of the coupling waveform during the period from Point A in the above diagram until the rising edge of RG. In addition, VRGL is the average value of VRGLH and VRGLL.

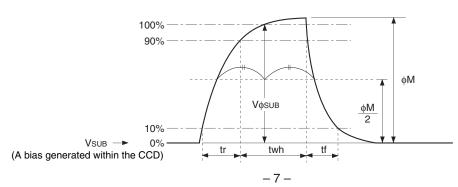
$$V_{RGL} = (V_{RGLH} + V_{RGLL})/2$$

Assuming VRGH is the minimum value during the interval twh, then:

$$V \phi RG = V RGH - V RGL$$

Negative overshoot level during the falling edge of RG is VRGLm.

(5) Substrate clock waveform





Clock Switching Characteristics

Item		Symbol		twh			twl			tr			tf			Remarks
	пеш	Symbol	Min.	Тур.	Мах.	Unit	nemarks									
Rea	dout clock	VT	2.3	2.5						0.5			0.5		μs	During readout
Ver	tical transfer k	Vφ1, Vφ2, Vφ3, Vφ4										15		250	ns	*1
_ <u>Ş</u>	During imaging	Нф1	26	28.5		26	28.5			6.5	9.5		6.5	9.5	- ns	*2
Horizontal transfer clock		Нф2	26	28.5		26	28.5			6.5	9.5		6.5	9.5		
loriz nsfe	During parallel-serial	Нф1		5.38						0.01			0.01			
ta Ta	conversion	Нф2					5.38			0.01			0.01		μs	
Res	et gate clock	φRG	11	13			51			3			3		ns	
Sub	strate clock	φSUB	1.5	1.8							0.5			0.5	μs	When draining charge

^{*1} When vertical transfer clock driver CXD1267AN is used.

^{*2} tf \geq tr - 2ns, and the cross-point voltage (VcR) for the H ϕ 1 rising side of the H ϕ 1 and H ϕ 2 waveforms must be at least V ϕ H/2 [V].

Item	Symbol		two		Unit	Remarks	
item	Gyrribor	Min.	Тур.	Max.	Offic	nemarks	
Horizontal transfer clock	Hф1, Hф2	22	26		ns	*3	

^{*3} The overlap period for twh and twl of horizontal transfer clocks $H\phi_1$ and $H\phi_2$ is two.

 $(Ta = 25^{\circ}C)$

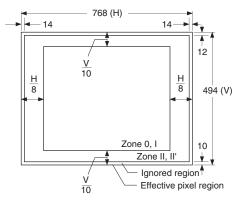


Image Sensor Characteristics

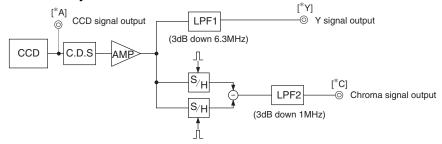
ICX408AK

Item	Symbol	Min.	Тур.	Max.	Unit	Measurement method	Remarks
Sensitivity	S	760	950		mV	1	
Sensitivity ratio	RмgG	0.93		1.35		2	
Sensitivity ratio	RYeCy	1.15		1.48		2	
Saturation signal	Ysat	1000			mV	3	Ta = 60°C
Smear	Sm		-110	-93	dB	4	
Video signal shading	SHy			20	%	5	Zone 0 and I
Video signal shading	ЗПУ			25	%	5	Zone 0 to II'
Uniformity between video	ΔSr			10	%	6	
signal channels	ΔSb			10	%	6	
Dark signal	Ydt			2	mV	7	Ta = 60°C
Dark signal shading	ΔYdt			1	mV	8	Ta = 60°C
Flicker Y	Fy			2	%	9	
Flicker R-Y	Fcr			5	%	9	
Flicker B-Y	Fcb			5	%	9	
Line crawl R	Lcr			3	%	10	
Line crawl G	Lcg			3	%	10	
Line crawl B	Lcb			3	%	10	
Line crawl W	Lcw			3	%	10	
Lag	Lag			0.5	%	11	

Zone Definition of Video Signal Shading



Measurement System



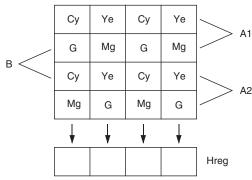
Note) Adjust the amplifier gain so that the gain between [*A] and [*Y], and between [*A] and [*C] equals 1. **-9-**

Image Sensor Characteristics Measurement Method

Measurement conditions

- 1) In the following measurements, the device drive conditions are at the typical values of the bias and clock voltage conditions.
- 2) In the following measurements, spot blemishes are excluded and, unless otherwise specified, the optical black level (OB) is used as the reference for the signal output, which is taken as the value of Y signal output or chroma signal output of the measurement system.

Color coding of this image sensor & Composition of luminance (Y) and chroma (color difference) signals



Color Coding Diagram

As shown in the left figure, fields are read out. The charge is mixed by pairs such as A1 and A2 in the A field. (pairs such as B in the B field)

As a result, the sequence of charges output as signals from the horizontal shift register (Hreg) is, for line A1, (G + Cy), (Mg + Ye), (G + Cy), and (Mg + Ye).

These signals are processed to form the Y signal and chroma (color difference) signal. The Y signal is formed by adding adjacent signals, and the chroma signal is formed by subtracting adjacent signals. In other words, the approximation:

$$Y = \{(G + Cy) + (Mg + Ye)\} \times 1/2$$

= 1/2 {2B + 3G + 2R}

is used for the Y signal, and the approximation:

$$R - Y = \{(Mg + Ye) - (G + Cy)\}\$$

= $\{2R - G\}$

is used for the chroma (color difference) signal. For line A2, the signals output from Hreg in sequence are

$$(Mg + Cy), (G + Ye), (Mg + Cy), (G + Ye).$$

The Y signal is formed from these signals as follows:

$$Y = \{(G + Ye) + (Mg + Cy)\} \times 1/2$$

= 1/2 {2B + 3G + 2R}

This is balanced since it is formed in the same way as for line A1.

In a like manner, the chroma (color difference) signal is approximated as follows:

$$-(B-Y) = \{(G + Ye) - (Mg + Cy)\}\$$

= $-\{2B-G\}$

In other words, the chroma signal can be retrieved according to the sequence of lines from R - Y and - (B - Y) in alternation. This is also true for the B field.

Definition of standard imaging conditions

1) Standard imaging condition I:

Use a pattern box (luminance 706cd/m^2 , color temperature of 3200K halogen source) as a subject. (Pattern for evaluation is not applicable.) Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter and image at F5.6. The luminous intensity to the sensor receiving surface at this point is defined as the standard sensitivity testing luminous intensity.

2) Standard imaging condition II:

Image a light source (color temperature of 3200K) with a uniformity of brightness within 2% at all angles. Use a testing standard lens with CM500S (t = 1.0mm) as an IR cut filter. The luminous intensity is adjusted to the value indicated in each testing item by the lens diaphragm.

1. Sensitivity

Set to standard imaging condition I. After selecting the electronic shutter mode with a shutter speed of 1/250s, measure the Y signal (Ys) at the center of the screen and substitute the value into the following formula.

$$S = Ys \times \frac{250}{60} [mV]$$

2. Sensitivity ratio

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the Mg signal output (SMg [mV]) and G signal output (SG [mV]), and Ye signal output (SYe [mV]) and Cy signal output (SCy [mV]) at the center of the screen with frame readout method. Substitute the values into the following formula.

$$R_{MgG} = S_{Mg}/S_{G}$$

 $R_{YeCy} = S_{Ye}/S_{Cy}$

3. Saturation signal

Set to standard imaging condition II. After adjusting the luminous intensity to 10 times the intensity with average value of the Y signal output, 200mV, measure the minimum value of the Y signal.

4. Smear

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity to 500 times the intensity with average value of the Y signal output, 200mV. When the readout clock is stopped and the charge drain is executed by the electronic shutter at the respective H blankings, measure the maximum value YSm [mV] of the Y signal output and substitute the value into the following formula.

$$Sm = 20 \times log \left(\frac{YSm}{200} \times \frac{1}{500} \times \frac{1}{10} \right) \text{ [dB] (1/10V method conversion value)}$$

5. Video signal shading

Set to standard imaging condition II. With the lens diaphragm at F5.6 to F8, adjust the luminous intensity so that the average value of the Y signal output is 200mV. Then measure the maximum (Ymax [mV]) and minimum (Ymin [mV]) values of the Y signal and substitute the values into the following formula.

SHy =
$$(Ymax - Ymin)/200 \times 100 [\%]$$

6. Uniformity between video signal channels

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the maximum (Crmax, Cbmax [mV]) and minimum (Crmin, Cbmin [mV]) values of the R - Y and B - Y channels of the chroma signal and substitute the values into the following formula.

$$\Delta Sr = | (Crmax - Crmin)/200 | \times 100 [\%]$$

 $\Delta Sb = | (Cbmax - Cbmin)/200 | \times 100 [\%]$



7. Dark signal

Measure the average value of the Y signal output (Ydt [mV]) with the device ambient temperature 60°C and the device in the light-obstructed state, using the horizontal idle transfer level as a reference.

8. Dark signal shading

After measuring 7, measure the maximum (Ydmax [mV]) and minimum (Ydmin [mV]) values of the Y signal output and substitute the values into the following formula.

$$\Delta Ydt = Ydmax - Ydmin [mV]$$

9. Flicker

1) Fy

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then measure the difference in the signal level between fields (Δ Yf [mV]). Then substitute the value into the following formula.

$$Fy = (\Delta Yf/200) \times 100 [\%]$$

2) Fcr, Fcb

Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, insert an R or B filter, and then measure both the difference in the signal level between fields of the chroma signal (Δ Cr, Δ Cb) as well as the average value of the chroma signal output (CAr, CAb). Substitute the values into the following formula.

Fci =
$$(\Delta \text{Ci/CAi}) \times 100 \, [\%] \, (i = r, b)$$

10. Line crawls

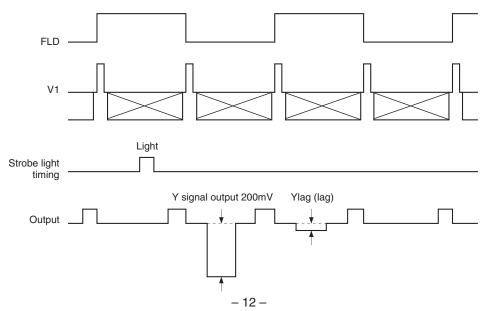
Set to standard imaging condition II. Adjust the luminous intensity so that the average value of the Y signal output is 200mV, and then insert a white subject and R, G, and B filters and measure the difference between Y signal lines for the same field (Δ Ylw, Δ Ylr, Δ Ylg, Δ Ylb [mV]). Substitute the values into the following formula.

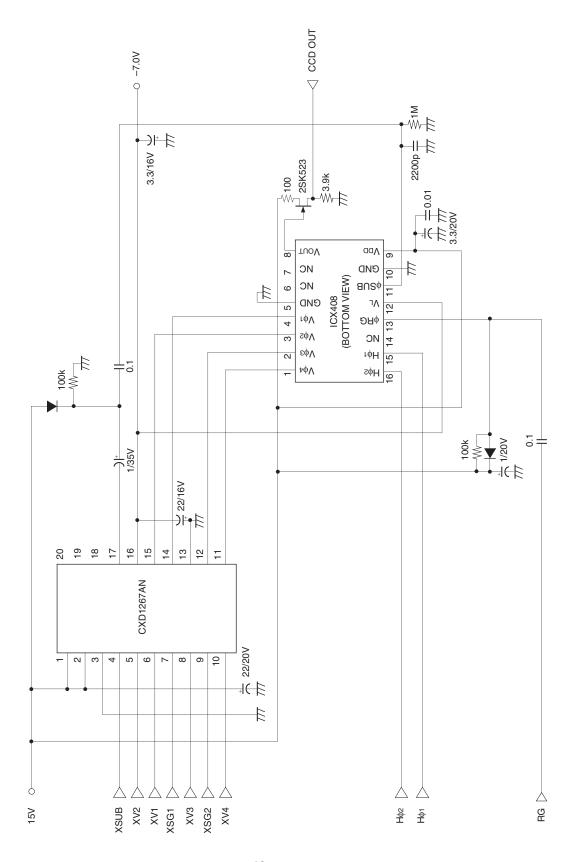
$$Lci = (\Delta Y li/200) \times 100 [\%] (i = w, r, g, b)$$

11. Lag

Adjust the Y signal output value generated by strobe light to 200mV. After setting the strobe light so that it strobes with the following timing, measure the residual signal (Ylag). Substitute the value into the following formula.

$$Lag = (Ylag/200) \times 100 [\%]$$

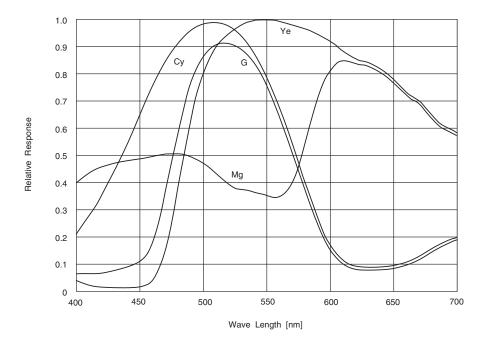




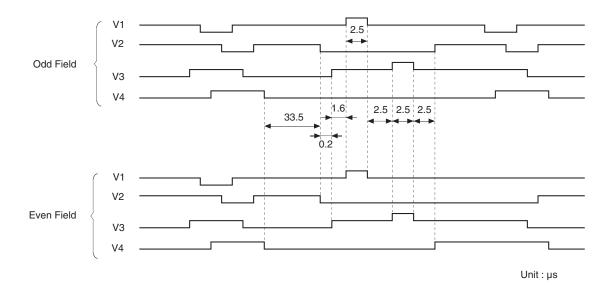
Drive Circuit

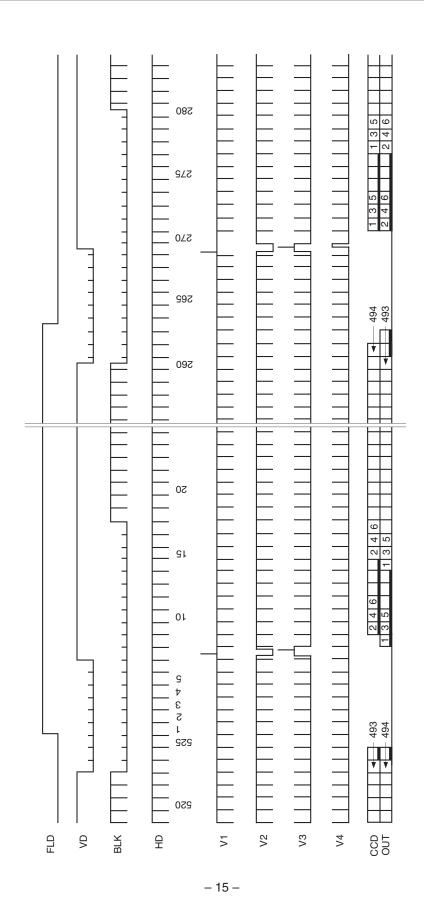


Spectral Sensitivity Characteristics (excludes both lens characteristics and light source characteristics)

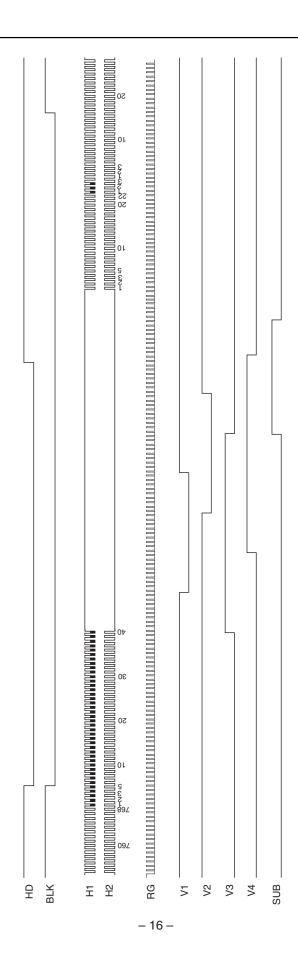


Sensor Readout Clock Timing Chart











Notes on Handling

1) Static charge prevention

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material.
 Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

2) Soldering

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

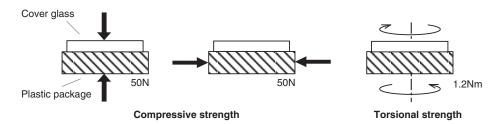
3) Dust and dirt protection

Image sensors are packed and delivered by taking care of protecting its glass plates from harmful dust and dirt. Clean glass plates with the following operation as required, and use them.

- a) Perform all assembly operations in a clean room (class 1000 or less).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.
- e) When a protective tape is applied before shipping, just before use remove the tape applied for electrostatic protection. Do not reuse the tape.

4) Installing (attaching)

a) Remain within the following limits when applying a static load to the package. Do not apply any load more than 0.7mm inside the outer perimeter of the glass portion, and do not apply any load or impact to limited portions. (This may cause cracks in the package.)

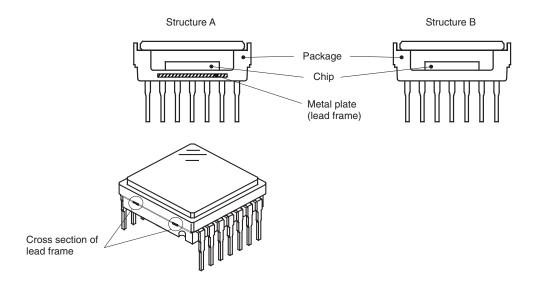


b) If a load is applied to the entire surface by a hard component, bending stress may be generated and the package may fracture, etc., depending on the flatness of the bottom of the package. Therefore, for installation, use either an elastic load, such as a spring plate, or an adhesive.

- c) The adhesive may cause the marking on the rear surface to disappear, especially in case the regulated voltage value is indicated on the rear surface. Therefore, the adhesive should not be applied to this area, and indicated values should be transferred to the other locations as a precaution.
- d) The notch of the package is used for directional index, and that can not be used for reference of fixing. In addition, the cover glass and seal resin may overlap with the notch of the package.
- e) If the lead bend repeatedly and the metal, etc., clash or rub against the package, the dust may be generated by the fragments of resin.
- f) Acrylate anaerobic adhesives are generally used to attach CCD image sensors. In addition, cyanoacrylate instantaneous adhesives are sometimes used jointly with acrylate anaerobic adhesives. (reference)

5) Others

- a) Do not expose to strong light (sun rays) for long periods, color filters will be discolored. When high luminance objects are imaged with the exposure level control by electronic-iris, the luminance of the image-plane may become excessive and discolor of the color filter will possibly be accelerated. In such a case, it is advisable that taking-lens with the automatic-iris and closing of the shutter during the power-off mode should be properly arranged. For continuous using under cruel condition exceeding the normal using condition, consult our company.
- b) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.
- c) The brown stain may be seen on the bottom or side of the package. But this does not affect the CCD characteristics.
- d) This package has 2 kinds of internal structure. However, their package outline, optical size, and strength are the same.



The cross section of lead frame can be seen on the side of the package for structure A.

